Electronic Supplementary Material (ESI) for Nanoscale.

Crystallographic orientation of facets and planar defects in functional nanostructures elucidated by nano-focused coherent diffractive x-ray imaging

(SUPPLEMENTARY MATERIAL)

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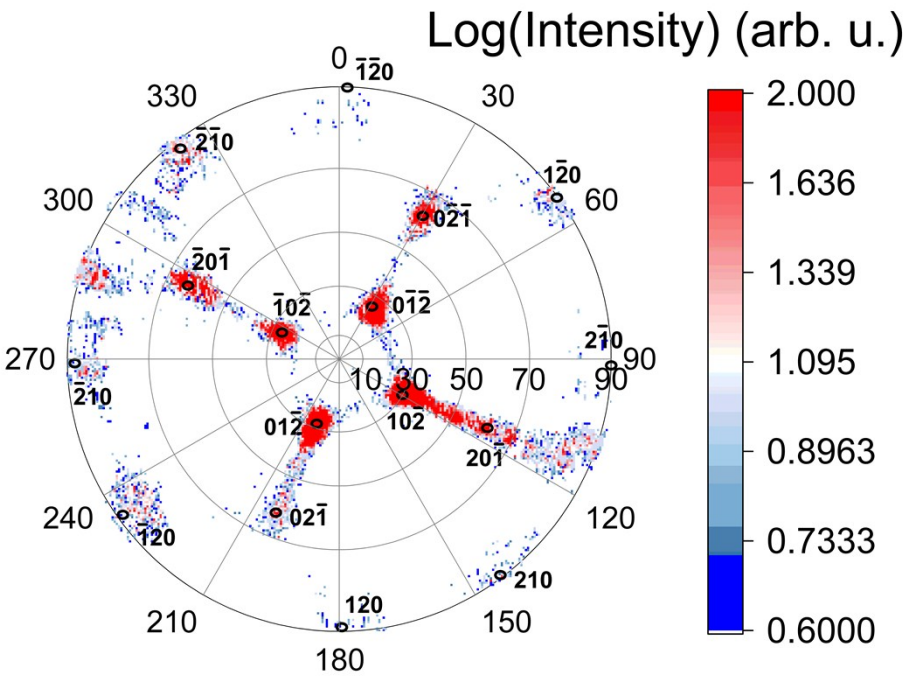

Figure S1: Stereographic projection of the 3D reciprocal space map around the **200** Pt Bragg reflection of an individual tetrahedrahexal (THH) Pt particle for r = 0.023 Å^{-1} and Δr = 0.0005 Å^{-1}. The **100** Pt pole is at the center of the polar figure. The position of the **201**-type poles are indicated by circles.

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